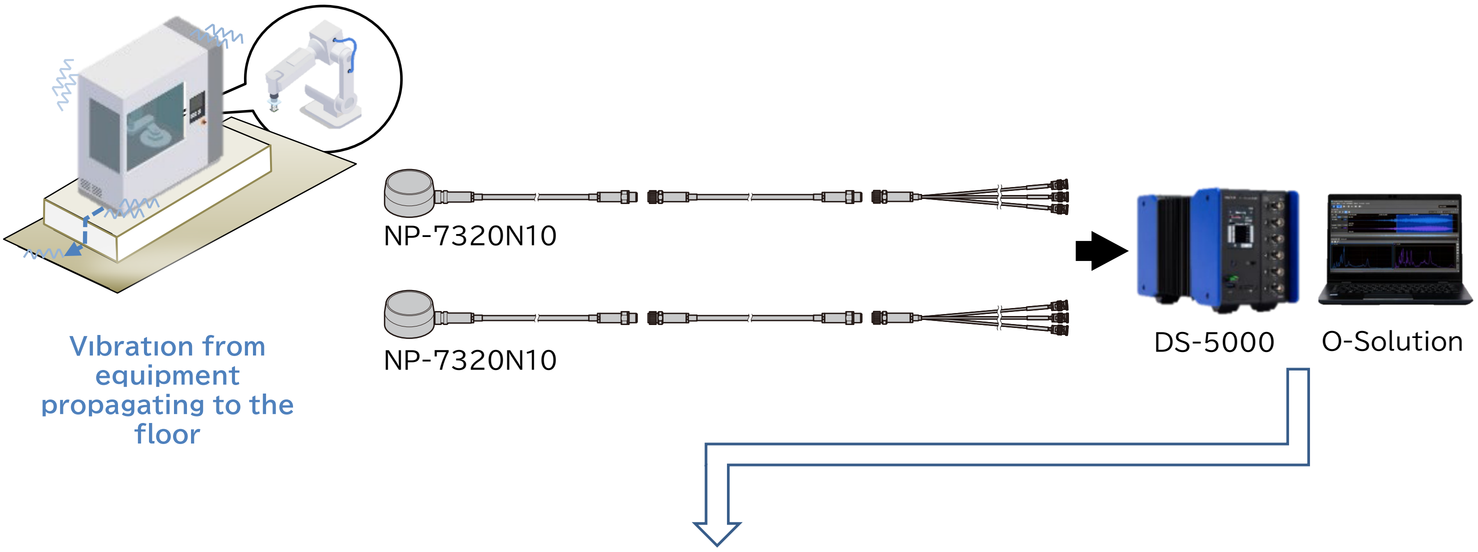
Floor vibration measurement of semiconductor manufacturing equipment

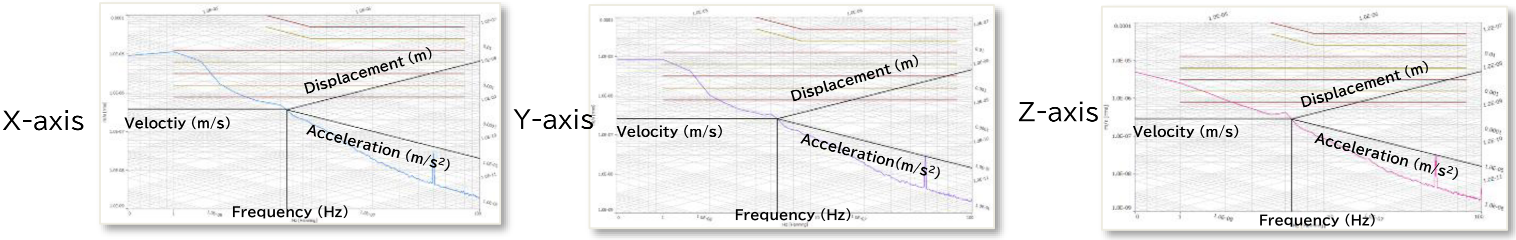
Overview

It has been proposed to use tripartite graphs and VC curves to evaluate the vibration environment of floors on which precision equipment such as semiconductor manufacturing equipment and electron microscopes are installed. With the NP-7320N10 and the DS-5000, this system allows to measure floor vibration at multi points simultaneously.
The O-Solution enables to display multiple VC curves to efficiently grasp the floor condition.
This system can also perform basic sound and vibration measurements, such as transmission characteristics from the surface block to the installation floor.

Measurement



Multiple Tripartite graphs displayed and compared simultaneously



*Contents of this document may change without prior notice.